

PROVISIONAL

IRFK6H/J054

Isolated Base Power HEX-pak[™]

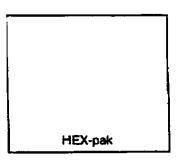
Assembly - Parallel Chip

- High Current Capability.
- UL recognized E78996.
- Electrically Isolated Base Plate.
- Easy Assembly into Equipment.

V _{DSS} = 60V
$R_{DS(on)} = 3.3m\Omega$
I _D = 350A

Description

The HEX-pakTM utilizes the well-proven HEXFETTM transistor die, combining low on-state resistance with high transconductance. These superior technology die are assembled by state of the art techniques into the TO-240 package, featuring 2.5kV ms isolation and solid M5 screw connections. The small footprint means the package is highly suited to power applications where space is a premium. Available in two versions, IRFK.H... for fast switching and IRFK.J... for oscillation sensitive applications.



Absolute Maximum Ratings

	Parameter	Max.	Units	
ID @ TC = 25°C	. Continuous Drain Current, V _{GS} @ 10V ©	350		
I ₂ T _C = 100°C	Continuous Drain Current, VGS @ 10V 0	220	Α ,	
1 _{DM}	Pulsed Drain Current ©	1400		
	Linear Derating Factor	5.0	W/C	
Pp @Tc = 25°C	Power Dissipation	625	W	
V _{GS}	Gate-to-Source Vottage	±20	, A	
V _{IN}	R.M.S. Isolation Voltage,	2.5	kV	
	Circuit to Base (1 Minute)			
TJ	Operating Junction and	-40 to 150	%	
T _{STG}	Storage Temperature Range			

Thermal Resistance

	Parameter	Min.	Тур.	Max.	Units
Rauc_	Junction-to-Case		- 1	0.20	-: °C/W
Recs	Case-to-Sink, Flat, Greased Surface		' 0.10 ;		_ •
_	Mounting torque +10%, M6 Screw Ø		. 5.0		Nm
[1	Busbar to HEXPAK with M5 Screw		3.0		
wt	Approximate Weight	_	140 (5.0)		; g (oz)



Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	i	Min.	Тур.	Max.	Units.	Conditions
V(BR)DSS	Drain-to-Source Breakdov	vn Voltage	60		\Box		V _{GS} = 0V, iD = 1.0mA
Ros(on)	Static Drain-to-Source On-Resistance @			2.2	3.3	mΩ	V _{GS} = 10V. I _D = 110A €
D(ON)	On State Drain Current		150			A	VDS > ID(ON)XRDS(ON)Max, VGS = 10V
VGS(th)	Gate Threshold Voltage		2.0	1—	4.0	i V	$V_{DS} = V_{GS}, I_D = 1.0 \text{mA}$
9/s	Forward Transconductan	св Ф	186	282		S	$V_{DS} = 50V$, $I_D = 225A$
	Drain-to-Source Leakage Current			T	1.5	mA	V _{DS} = 60V. V _{GS} = 0V
IDSS				_	6.0]	$V_{DS} = 48V$, $V_{GS} = 0V$. $T_J = 125$ °C
l .	Gate-to-Source Forward Leakage				600	nA	V _{GS} = 20V
GSS	Gate-to-Source Reverse	Leakage			-600		V _{GS} = -20V
Q,	Total Gate Charge			780	900	[I _D = 225A
Qgs	Gate-to-Source Charge			150	220	nC i	V _{DS} ≈ 48V
Q _{pd}	Gate-to-Drain ("Miller") C	harge	_	270	400	<u> </u>	V _{GS} = 10V &
t _{okan)}	ium-On Delav ime ⊨	IRFK6H054	<u> </u>	110	<u> </u>]	
-CKON)		IRFK6J054		125	_		1
ŧ,	Rise Time	IRFK6H054	<u> </u>	700	<u> </u>	ns	V ₀₀ = 25V
¬		1RFK6J054	<u>! — </u>	800	<u> </u>		I _D = 225A
takain	Turn-Off Delay Time	IRFK6H054	=	(400	1=	1	V _{GS} = 10V
		IRFK6J054	1=	530	<u> </u>	<u>.</u>	R _S = 3.3Ω ③
ų	Fa# IIme ⊩	IRFK6H054	<u> </u>	260	<u> — </u>		
		IRFK6J054	!=	300			<u> </u>
Los	S Drain Inductance to Source			18	<u> </u>	nH	
C ₁₅₅	Input Capacitance		<u> </u>	14		j	V _{GS} = 0V
C _{ces}	Output Capacitance		_	2.5	<u> </u>	nF	V _{OS} = 25V
Crss	Reverse Transfer Capac	itance	I —	0.75			f = 1.0MHz

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
s	Continuous Source Current (Body Diode)	\ <u> </u>		300		Modified MOSFET symbol showing the integral reverse p-n junction diode.
SM	Pulsed Source Current (Body Diode) ©		-	1100	1 ^	
V _{SD}	Diode Forward Voltage		1	2.5	ν	T _J = 25°C, l _S = 225A, V _{GS} = 0V @
t _r	Reverse Recovery Time	71	150	, 320	ns	T _J = 25°C, 1 _F = 225A
Q _{rr}	: Reverse RecoveryCharge	4.4	1 10	23	μC	di/dt ≈ 400A/µs ®

Notes:

- ① Repetitive rating; pulse width limited by maximum junction temperature.
- ② A mounting compound is recommended and the torque should be rechecked after a period of three hours to allow for the spread of the compound.
- 3 Limited by package to 200 amperes maximum continuous current.
- Pulse width ≤ 300µs; duty cycle ≤ 2%.